

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS80C320	Dec-96	9638 B3	ANAM, K.	DN633478AAA1	0.8μ OX/NI	44 PLCC

**STRESS/JOB NO.**

**READPOINT  
(Sample Size/No. of Fails)**

Preconditioning (P/C):  
HTC Vapor Phase  
P-18757

<u>Electrical</u>	<u>Cum %</u>
233/0	0.0%

Sonoscan  
P-18796

<u>Post Vapor Phase</u>
4/0

Infant / High Voltage Life  
125°C, 7.0 V.  
P-18797, P-18810

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
228/0	77/0	77/0	30 Fits

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle  
-55°C to +125°C  
P-18811

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
49/0	49/0	0.0%

Biased Moisture (HAST)  
120°C/85% RH, 5.5 V.  
P-18812

<u>100 Hr</u>	<u>Cum %</u>
60/0	0.0%

Autoclave  
121°C/100% RH, 2 Atmos  
P-18813

<u>96 Hr</u>	<u>Cum %</u>
42/0	0.0%

**Failure Mode**

**Failure Analysis**